

Notice of References Cited	Application/Control No. 09/900,779	Applicant(s)/Patent Under Reexamination BRAND ET AL.	
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	W	Hobbs, Gregg. "What HALT and HASS Can Do For Your Products". © 1997, Nelson Publishing. http://www.evaluationengineering.com/archive/articles/1197halt.htm
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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